



EV085415195

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 09/388,063
Filing Date August 30, 1999
Inventor Vishnu K. Agarwal, et al.
Assignee Micron Technology, Inc.
Group Art Unit 2815
Examiner J. Fenty
Attorney's Docket No. MI22-1196
Title: Capacitors Having a Capacitor Dielectric Layer Comprising a Metal Oxide Having
Multiple Different Metals Bonded with Oxygen.

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT


The Examiner's attention is directed to the reference which is listed on the attached Form PTO-1449, a copy of which is attached. No admission is made regarding whether all the submitted references are prior art.

Citation of the referenced art is respectfully requested.

This Supplemental Information Disclosure Statement is being filed before the mailing date of a first Office Action after filing of an RCE. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

Respectfully Submitted:

Dated: 7-11-03

By: 
D. Brent Kenady
Reg. No. 40,045

Form PT 119		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1196		SERIAL NO. 09/388.063	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vishnu K. Agarwal			
				FILING DATE August 30, 1999		GROUP 2815	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5.711.816	01/27/1998	KIRLIN, ET AL	118	726	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER				DATE CONSIDERED			
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							



FV318282177

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References -- See Attached Form PTO-1449

This Request for Continued Examination (RCE) Application is being filed in an abundance of caution to ensure consideration of the references listed on the attached form PTO-1449.

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No admission is made regarding whether the submitted references are prior art.

Respectfully Submitted:

Dated: 9-5-03

By: 
D. Brent Kenady
Reg. No. 40,045

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1196		SERIAL NO. 09/388,063			
<div style="position: relative; height: 100px;"> <div style="position: absolute; top: 0; left: 0; width: 100%; height: 100%; border: 2px solid black; border-radius: 50%; text-align: center; color: black; font-weight: bold; font-size: 1.2em;"> OFFICE SEP 05 2003 PATENT & TRADEMARK OFFICE </div> </div>				LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vishnu K. Agarwal	
				FILING DATE August 30, 1999		GROUP 2815			
U.S. PATENT DOCUMENTS									
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate			
	AA	6,372,686 B1	04/16/02	Golden					
	AB	6,338,970 B1	01/15/02	Suh					
	AC								
	AD								
	AE								
	AF								
	AG								
	AH								
	AI								
	AJ								
	AK								
	AL								
FOREIGN PATENT DOCUMENTS									
		Document Number	Date	Country	Class	Subclass	Translation		
							Yes No		
	AM								
	AN								
	AO								
	AP								
	AQ								
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
	AR								
	AS								
	AT								
EXAMINER				DATE CONSIDERED					
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